Electron Confinement in Graphene Nanoislands with Free-electron-like Energy Dispersion

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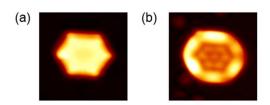


Figure. S1. (a) STM image of a GN with hexagonal shape ($V_s = 0.1 \text{ V}$, $I_t = 1.0 \text{ nA}$, Scan area: $5.5 \times 5.5 \text{ nm}^2$). (b) dI/dV map measured at the sample bias voltage of 3.9 V.

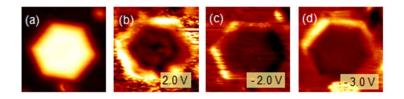


Figure. S2. (a) STM image of the GN ($V_s = -2.0 \text{ V}$, $I_t = 1.0 \text{ nA}$, Scan area: $4.5 \times 4.5 \text{ nm}^2$). (b) - (d) dI/dV maps.

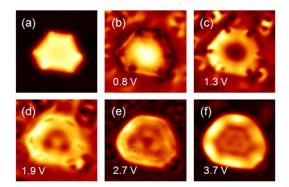


Figure. S3. (a) STM image of the GN ($V_s = 0.01 \text{ V}$, $I_t = 7.0 \text{ nA}$, Scan area: $5 \times 5 \text{ nm}^2$). (b) – (f) dI/dV maps.